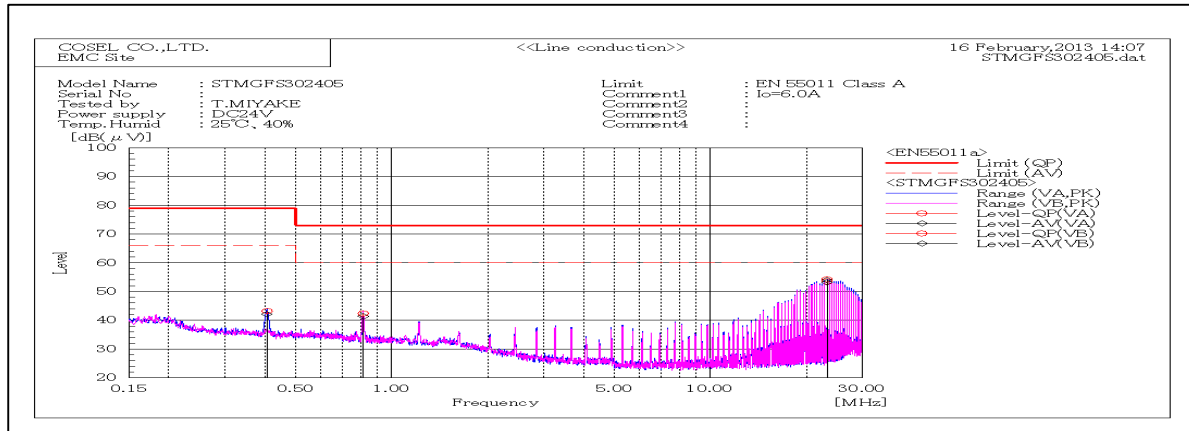
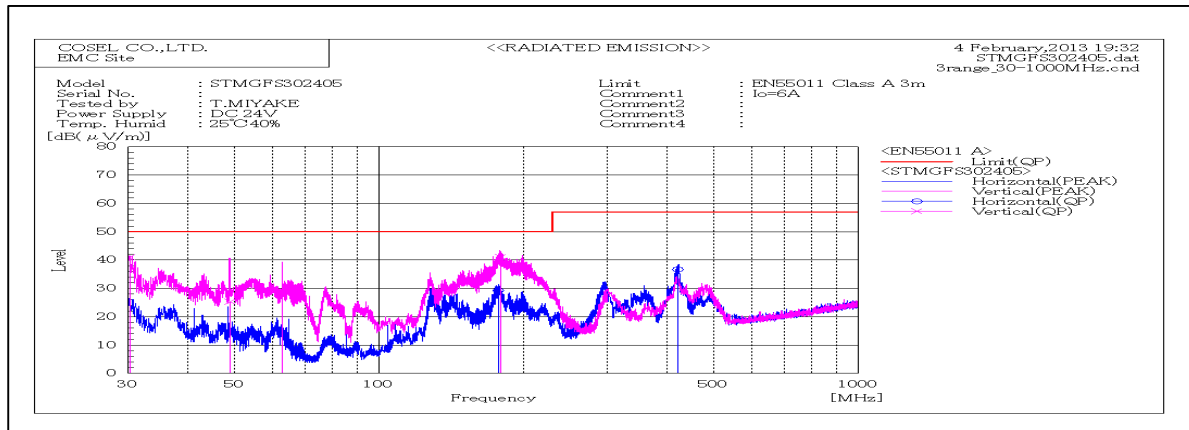


DATA SHEET		Date	18-Feb-13
Model	STMGFS302405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



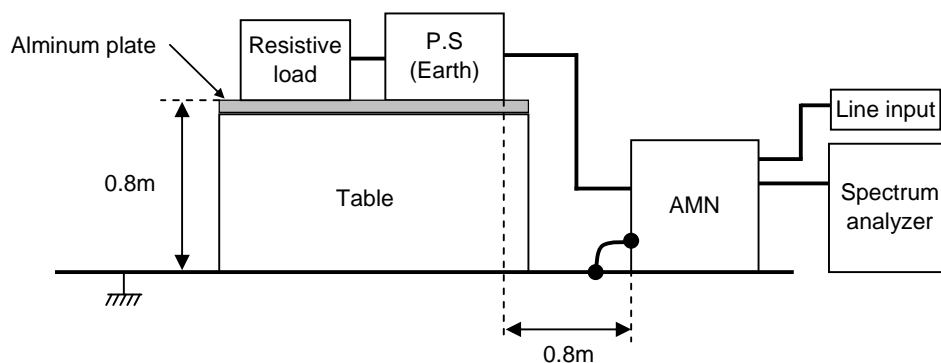
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40635		VA	23.1	22	20.1	43.2	42.1	79	66	35.8	23.9	Pass	
0.81379		VB	22.3	21.3	20.1	42.4	41.4	73	60	30.6	18.6	Pass	
23.19205		VA	33.1	32.9	21.1	54.2	54	73	60	18.8	6	Pass	
23.19295		VB	32.4	32.1	21.1	53.5	53.2	73	60	19.5	6.8	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.191	V	Stable	54.4	-13.5	40.9	50	9.1	Pass	113	108		
48.922	V	Stable	48.9	-23.6	25.3	50	24.7	Pass	102	28		
62.811	V	Stable	52.2	-23.5	28.7	50	21.3	Pass	110	42		
177.483	H	Stable	51.5	-22.3	29.2	50	20.8	Pass	154	83		
179.152	V	Stable	57.1	-16	41.1	50	8.9	Pass	108	270		
420.771	H	Stable	50.8	-14.1	36.7	57	20.3	Pass	102	92		

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

